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HIGH SPEED SURFACE CHARACTERIZATION _____ of an ______ OYSTER SHELL



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INTRODUCTION

Large samples with complex geometries can prove difficult to work with due to sample preparation, size, sharp angles, and curvature. In this study an oyster shell will be scanned to demonstrate the Nanovea HS2000 Line Sensor's capability to scan a large, biological sample with complex geometry. While a biological sample was used in this study, the same concepts can be applied to other samples.

IMPORTANCE OF 3D NON CONTACT PROFILOMETRY ON AN OYSTER SHELL

By scanning the whole surface of an oyster shell, the Nanovea HS2000 Line Sensor will display its ability to work with large samples with unique geometries. Typically, samples need to be securely mounted to the stage to mitigate their displacement as the stage moves. This usually requires additional sample preparation or a fixture to be used. But with the smooth air bearing stages on the Nanovea HS2000, little to no sample preparation is needed to begin your tests.

Patching, shown in this study, allows the Nanovea HS2000 Line Sensor to capture a surface that has features taller than the optical sensors height range or the instruments lateral range. This is accomplished by taking multiple scans at varying heights and overlaying them at their relative offsets. And with the stages' 3 axis motion control, you can index in specified steps in the z direction to quicken the process.

Measurement Objectives

Equipment Featured

NANOVEA HS2000L



High Speed Inspection & Precision Flatness Measurement Advanced Automation with customizable options High-speed data collection, up to 384k points per second Designed for large area flatness measurement Full granite base with integrated anti-vibration table Learn More about the HS2000

Measurement Objectives

In this application, an oyster shell was scanned using the Nanovea HS2000 Line Sensor. Multiple scans were conducted at various heights and reconstructed via patching to represent the whole shell.



Measurement Parameters

Oyster Shell	
Optical Pen Acquisition rate Averaging Measured surface Step size Measurement Time (h:m:s)	L3 400 pps 1 140mm x 90mm 25µm x 25µm 00:05:31

Table 1: The following test parameters were used for each of the 9 scans performed for this study.

Sample Tested



Sample of Oyster Shell Tested

Results: Series of Surfaces

For this study, a total of 9 scans were conducted on the oyster shell to obtain height data over the whole surface. The individual scans are shown in a 3D view below.



Results: 3D Surface

The patched 2D and 3D surface can be observed below. We were able to obtain the whole surface of the oyster shell with the Nanovea HS2000 Line Sensor without compromising on the resolution. Small features on the shell's surface can still be seen in the 3D view.



Results: Surface Roughness Analysis

Below is the surface roughness of the oyster shell, this was obtained by applying a gaussian filter of 1.5mm. This excludes form (or waviness) larger than the cut-off index, leaving behind features that represent the oyster shells roughness. Despite the lack of a fixture, stage noise was not observed in the surface roughness analysis.



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Conclusion

A total of 9 scans were used in this study to recreate the surface of the oyster shell using the Nanovea HS2000 Line Sensor. From the patched surface, the roughness of the oyster shell was measured by removing the form (or waviness) of the sample. Patching can also be used to measure much finer roughnesses on a large sample that would normally be beyond the optical sensors height range. Large conical lenses, for example, require a very fine step size in order to quantify microscopic features that can be present. The Nanovea HS2000 Line Sensor has shown it is able to conduct profilometry measurements on large samples with abnormal geometries while retaining high resolution with minimal sample preparation.

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